

Enhancement Mode N-Channel Power MOSFET

TO-252/NMOS/100V/±20V/1.85V/85A/6.6mΩ

Rev1.0





100V, 6.6mΩ, 85A, Single N-Channel

1.Features

- Super Low Gate Charge
- ◆ Green Device Available
- ◆ Excellent Cdv/dt effect decline
- ◆ Advanced high cell density Trench technology
- ◆ 100% RG Tested
- ◆ 100% UIS Tested

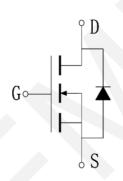
2.Applications

- Primary Side Switch
- ◆ Load Switch



Pin Description

V _{DS}	R _{DS(on)} Typ.	I _D Max.
100V	6.6mΩ @ 10V	054
	9.1mΩ @ 4.5V	85A



Schematic Diagram

3. Package Marking and Ordering Information

Part no.	Marking Package PCS/Reel		PCS/CTN.	
WX060N10KD	060N10	TO-252	2,500	25,000

4.Absolute Max Ratings at Ta=25°C (Note1)

Parameter	Symbol	Maximum	Units
Drain to Source Voltage	$V_{ extsf{DSS}}$	100	V
Gate to Source Voltage	V_{GSS}	±20	V
Drain Current (DC)	I_D	85	А
Drain Current (Pulse), PW≤300μs	I _{DP}	340	А
Total Dissipation	P_{D}	78	W
Avalanche Energy, Single Pulsed	E _{AS}	256	mJ
Junction Temperature	T_{j}	150	°C
Storage Temperature	T_{stg}	-55 to +150	°C

Note 1: Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.



5. Thermal Resistance Ratings (Note 2)

Parameter	Symbol	Value	Unit	
Junction to case	$R_{ heta JC}$	2.4	°C/W	
Junction to ambient	$R_{ hetaJA}$	29	°C/W	

Note 2: When mounted on 1 inch square copper board t ≤ 10sec The value in any given application depends on the user's specific board design.

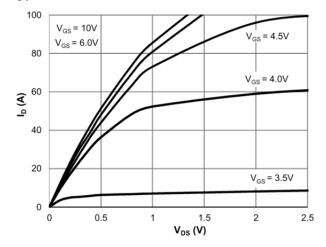
6.Electrical Characteristics at Ta=25°C (Note 3)

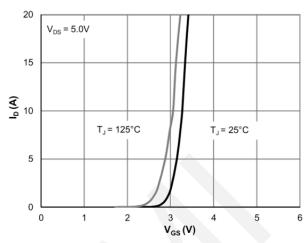
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Units
Drain to Source Breakdown Voltage	V _{(BR)DSS}	$I_D = 250 \mu A, V_{GS} = 0 V$	100	1	1	V
Zero-Gate Voltage Drain Current	I _{DSS}	V _{DS} = 100V, V _{GS} = 0V	ı	1	1	μA
Gate to Source Leakage Current	I _{GSS}	$V_{GS} = \pm 20V, V_{SS} = 0V$,	-	±100	nA
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}$, $I_{DS}=250\mu A$	1.2	1.85	2.2	V
Static Drain to Source On-State	R _{DS(on)}	I _D = 20A, V _{GS} = 10V	-	6.6	7.7	mΩ
Resistance	25(6)	I _D = 15A, V _{GS} = 4.5V	-	9.1	11	mΩ
Input Capacitance	C _{iss}	V _{GS} =0V,	-	1657	-	pF
Output Capacitance	C _{oss}	V _{DS} =40V,	-	965	-	pF
Reverse Transfer Capacitance	C_{rss}	Frequency=1.0MHz	ı	8	ı	pF
Turn-ON Delay Time	t _{d(on)}		ı	10.7	ı	ns
Rise Time	t _r	V_{DS} = 50V, R_{L} = 2.5 Ω V_{GS} = 10V, R_{GEN} =3.0 Ω	ı	21	ı	ns
Turn-OFF Delay Time	$t_{d(off)}$		-	31	-	ns
Fall Time	t _f		1	10.7	ı	ns
	Q_g	V _{DS} = 50V,	ı	36	1	nC
Total Gate Charge	Q_{gs}	$V_{GS} = 0$ to 10V,	-	7.8	1	nC
	Q_{gd}	I _D = 20A	-	8.8	-	nC
Diode Forward Voltage	V _{FSD}	I _S = 20A, V _{GS} = 0	-	-	1.2	V

Note 3: Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

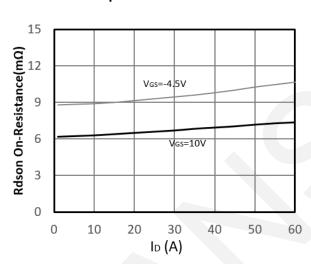


7. Typical electrical and thermal characteristics

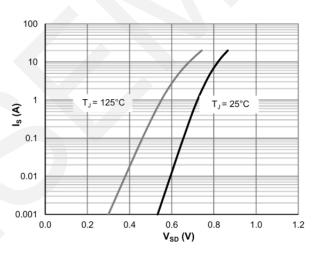




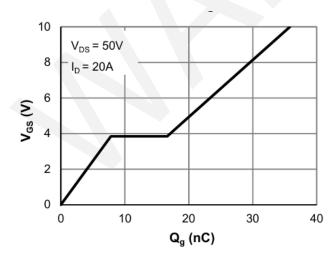
Output Characteristics



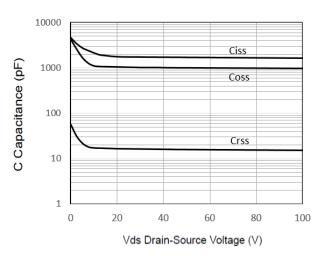
Transfer Characteristics



Rdson-Drain Current



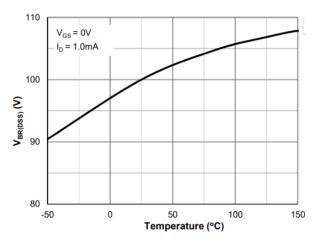
Body Diode Characteristics



Gate Charge

Capacitance Characteristics

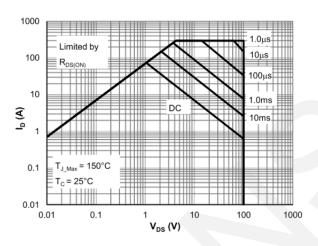


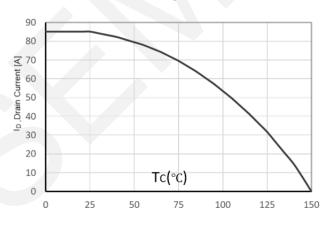


2.0 $V_{GS} = 10V$ 1.6 I_D = 20A Normalized R_{DS(ON)} 1.2 I_D = 15A 0.8 0.4 0.0 -50 0 50 100 150 Temperature (°C)

Normalized Breakdown voltage vs. Junction Temperature

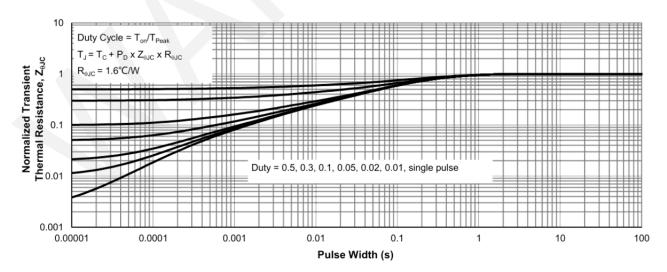
Normalized on Resistance vs. Junction Temperature





Maximum Safe Operating Area

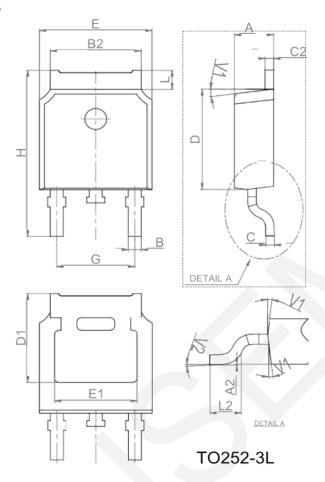
Maximum Continuous Drain Current - Case Temperature



Maximum Effective Transient Thermal Impedance, Junction-to-Case



8.Package Dimensions



	Dimensions						
Ref.	Millimeters			Inches			
	Min.	Тур.	Max.	Min.	Тур.	Max.	
Α	2.10		2.50	0.083		0.098	
A2	0		0.10	0		0.004	
В	0.66		0.86	0.026		0.034	
B2	5.18		5.48	0.202		0.216	
С	0.40		0.60	0.016		0.024	
C2	0.44		0.58	0.017		0.023	
D	5.90		6.30	0.232		0.248	
D1		5.30REF		0.209REF			
E	6.40		6.80	0.252		0.268	
E1	4.63			0.182			
G	4.47		4.67	0.176		0.184	
Н	9.50		10.70	0.374		0.421	
L	1.09		1.21	0.043		0.048	
L2	1.35		1.65	0.053		0.065	
V1		7°			7°		
V2	0°		6°	0°		6°	



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